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Wednesday, July 19, 2023

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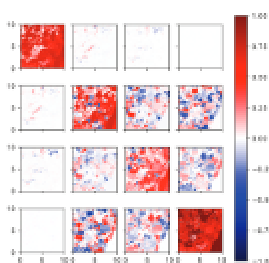
Polarization Metrology of Anisotropic Materials



Polarization Metrology of Anisotropic Materials

Full Mueller matrix measurements allow for elimination of ambiguity and a fuller understanding of polarization metrology. The Exicor® 150XT system offers complete Mueller matrix measurement from 350 nm to 800 nm with automated sample translation and optional tip-tilt measurements. Integration times as low as 0.01 seconds for measurements of the Mueller matrix to 0.001. Partial Mueller matrix systems can attain measurements of 8 Mueller parameters with precision of 0.0001.

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